Problem 1:

An integrated circuit manufacturer has three machines X, Y and Z. A circuit selected from each machine can be either defective (not acceptable) or non-defective (acceptable). Suppose we run an experiment by randomly picking three circuits in sequence from X, Y and Z, respectively. We test each one and record the observation as "a" if acceptable or "f" if it fails. For example, if the circuits from X and Y are acceptable (pass the test) but the circuit from Z is defective (fails the test), then the observation is aaf. Use set operations to answer the following questions:

- (a) What are the elements of the sample space of the experiment?
- (b) What are the elements of the set $A = \{\text{circuit from } Z \text{ fails}\}$
- (c) What are the elements of the set $B = \{\text{circuit from } X \text{ acceptable}\}$
- (d) Are A and B mutually exclusive? Why?
- (e) Are A and B collectively exhaustive? Why?
- (f) What are the elements of the set $D = \{\text{more than one circuit is acceptable}\}$?
- (g) What are the elements of the set $E = \{at \ least \ two \ circuits \ fail \}$?
- (h) Show whether D and E are mutually exclusive?
- (i) Show whether D and E are collectively exhaustive?

Problem 2:

Comparing all the events listed below, which events are equal?

- (a) $A = \{2,3\}$.
- (b) $B = \{0,1,2,3,4,5,6\}$.
- (c) $C = \{x \mid x^2 5x + 6 = 0\}$
- (d) $D = \{x \mid x \text{ is the number of heads when six coins are tossed}\}$

Problem 3:

Consider the following sets:

| $S = \{0,1,2,3,4,5,6,7,8,9\}$ | $A = \{0, 2, 4, 6, 8\}$ | $B = \{1,3,5,7,9\}$ |
|-------------------------------|-------------------------|---------------------|
| $C = \{2,3,4,5\}$ | $D = \{1, 6, 7\}$ | |

List the elements of the sets corresponding to the following events:

| (a) $A \cup C$ | (b) <i>A</i> ∩ <i>B</i> | (c) \overline{C} |
|------------------------------------|-----------------------------|----------------------------------|
| (d) $(\overline{C} \cap B) \cup D$ | (e) $\overline{(S \cap C)}$ | (f) $\overline{A} \cap C \cap D$ |

Problem 4:

Consider two non-disjoint events A and B and sample space S. Sketch Venn diagrams and shade the regions for each of the events resulting from the following operations:

| (a) $C = \overline{A \cap B}$ (b) $D = \overline{A \cup B}$ | (c) $A \cap \overline{B}$ |
|---|---------------------------|
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Problem 5:

From past experience, a stockbroker believes that under present economic conditions a customer will invest in bonds (event B) with a probability of 0.6, will invest in mutual funds (event M) with a probability of 0.3, and invest in both bonds (B) and mutual funds (M) with a probability of 0.15. Note that events are not disjoint or mutually exclusive. Find the probability that a customer will make

- (a) An investment in either bonds or mutual funds or both; (answer: 0.75)
- (b) No investment at all; (answer: 0.25).

Problem 6:

A cell phone manufacturer is concerned about a possible recall of its best-selling phone. If there were a recall, there is a probability 0.25 of a defect in the battery, 0.18 of a defect in the electronics, 0.17 of a defect in the operating system, and 0.40 of a defect in the display. Define events: A = defect in the battery and B = defect in the electronics, C = defect in the operating system and D = defect in display.

- (a) Find the probability that there is defect in the battery or the electronics, or both. The probability of defects in both battery and electronics, simultaneously, is $P[A \cap B] = 0.15$?
- (b) Find the probability that no defects will be involved in any of the two (battery or electronics).
- (c) Find the probability that a battery is defective, and the electronics are not defective? The probability of defects in both battery and electronics, simultaneously, is $P[A \cap B] = 0.15$? Note: $P[A \cap S] = P[A]$